

Search Notes



Application/Control No.

10/685,322

Examiner

Ren L. Yan

Applicant(s)/Patent under Reexamination

HIRST ET AL.

Art Unit

2854

SEARCHED

Class	Subclass	Date	Examiner
347	102 224		
361	103		
	200		
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101	483		
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372	29.012		
	29.015		
	34		
	36		
above search updated		1/31/07	RY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East text search	1/27/07	RY